





an Open Access Journal by MDPI

Smart Processing for Systems under Uncertainty or Perturbation

Guest Editors:

Dr. Sanghyuk Lee

Department of Electrical and Electronic Engineering, Xi'an Jiaotong-Liverpool University, Xi'an 215123, China

Prof. Dr. Mihail Popescu

University of Missouri, Columbia, MO 65211, USA

Dr. Eneko Osaba

Tecnalia Research & Innovation, 48160 Derio, Spain

Deadline for manuscript submissions:

closed (31 July 2021)

Message from the Guest Editors

With the development of artificial intelligence and learning algorithms, data processing and decision procedures have become possible for complex systems, large scale systems, and high-dimensional systems. Such achievements are supported by the development of high specification hardware. However, we are faced with output reliability issues due to variations in external inputs such as disturbances or uncertainty, because computation and processing relies on straight through processing. We are focusing on research into robust performance with respect to external inputs from smart devices such as smart sensors or smart actuators. Hence, we are emphasizing aspects that give rise to effective and efficient solutions involving control algorithms for the implementation of smart devices. Generally, finding an optimal or suboptimal solution for a complex process with internal or external variation is challenging. We hope this Special Issue provides the opportunity to share our research ideas related to data networking and process optimization for smart systems.











an Open Access Journal by MDPI

Editor-in-Chief

Prof. Dr. Flavio Canavero

Department of Electronics and Telecommunications, Politecnico di Torino, 10129 Torino, Italy

Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

Author Benefits

Open Access: free for readers, with article processing charges (APC) paid by authors or their institutions.

High Visibility: indexed within Scopus, SCIE (Web of Science), CAPlus / SciFinder, Inspec, Ei Compendex and other databases.

Journal Rank: JCR - Q2 (Physics, Applied) / CiteScore - Q2 (Control and Systems

Engineering)

Contact Us